

<b>Notice of References Cited</b>		Application/Control No. 10/815,280	Applicant(s)/Patent Under Reexamination SARNA, LALIT	
		Examiner YUBIN HUNG	Art Unit 2624	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,231,484	07-1993	Gonzales et al.	375/240.04
*	B	US-7,184,578	02-2007	Simon et al.	382/118
*	C	US-6,535,632	03-2003	Park et al.	382/164
*	D	US-2002/0186890	12-2002	Lee et al.	382/239
*	E	US-2003/0001964	01-2003	Masukura et al.	348/441
*	F	US-2003/0206664	11-2003	Gomila et al.	382/268
*	G	US-2005/0013359	01-2005	Srinivasan, Sridhar	375/240.03
*	H	US-7,266,149	09-2007	Holcomb et al.	375/240.12
*	I	US-2002/0165844	11-2002	Lee et al.	706/61
*	J	US-2002/0196355	12-2002	Hiroshige et al.	348/252
*	K	US-2008/0002902	01-2008	Lin et al.	382/261
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
*	U	Duda et al. (Pattern Classification and Scene Analysis, 1973; pp. 130-134)			
	V				
	W				
	X				

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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